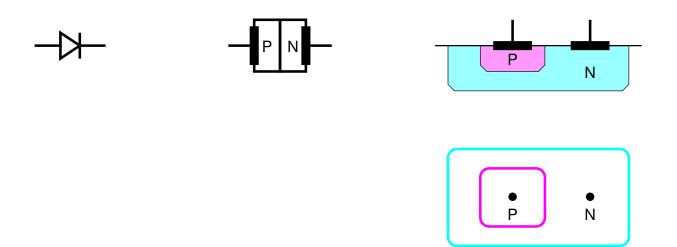
### **Diodes and Bipolar Transistors**

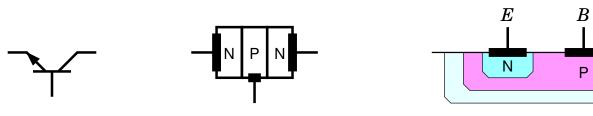
Diode

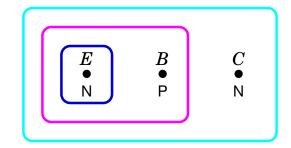


- Ideal structure 1D
- Real structure 3D
- Depth controlled implants.

### **Diodes and Bipolar Transistors**

NPN Transistor





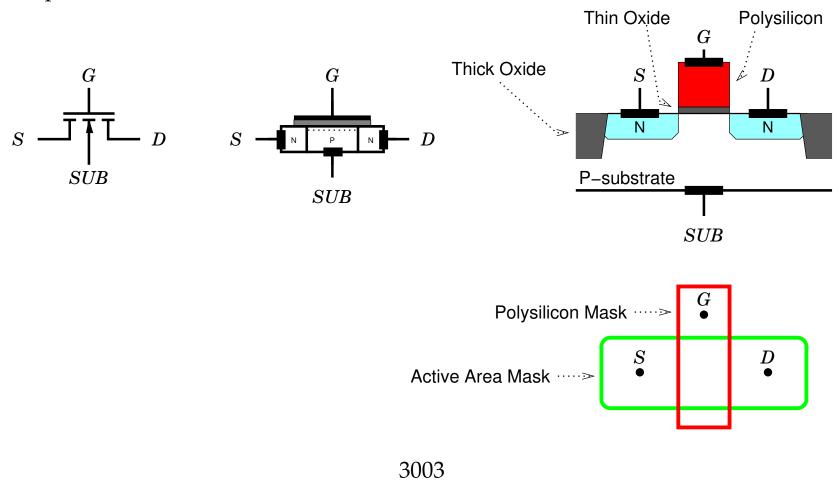
C

Ν

• Two n-type implants.

### **MOS** Transistors

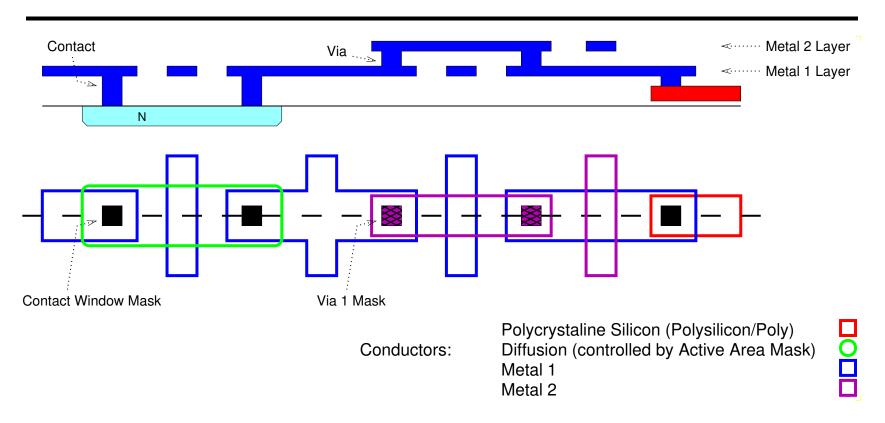
Simple NMOS Transistor



## Simple NMOS Transistor

- Active Area mask defines extent of *Thick Oxide*.
- Polysilicon mask also controls extent of *Thin Oxide* (alias *Gate Oxide*).
- N-type implant has no extra mask.
  - It is blocked by thick oxide and by polysilicon.
  - The implant is *Self Aligned*.
- Substrate connection is to bottom of wafer.
  - All substrates to ground.
- Gate connection not above transistor area.
  - Design Rule.

# Interconnect

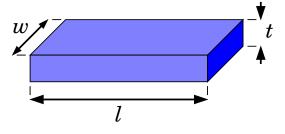


- Crossing conductors on different masks do not interact<sup>1</sup>.
  - Explicit contact/via is required for connection.
- Crossing conductors on the same mask are always connected.

<sup>&</sup>lt;sup>1</sup>the exception to this rule is that polysilicon crossing diffusion gives us a transistor

#### Interconnect

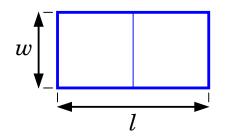
### Resistance



$$R = \left(\frac{\rho}{t}\right) \left(\frac{l}{w}\right)$$

where  $\rho$  is the resistivity constant  $3.2 \times 10^{-8} \Omega m$  for aluminium  $1.7 \times 10^{-8} \Omega m$  for copper

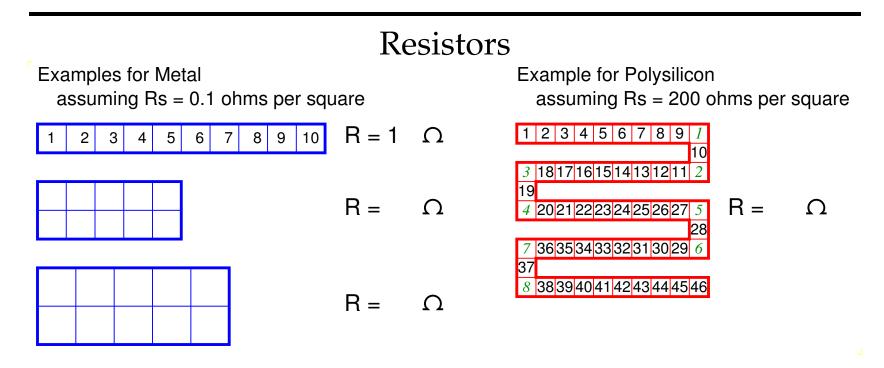
Since *t* and  $\rho$  are fixed for a paricular mask layer, the value that is normally used is the sheet resistance:  $R_s = \left(\frac{\rho}{t}\right)$ .



$$R = R_s \left(\frac{l}{w}\right)$$

where  $R_s$  is sheet resistance  $0.1\Omega/\Box$  for 170nm thick copper

 $R_s$  = resistance of a square (i.e. w = l) so the units for  $R_s$  are  $\Omega/\Box$  (ohms per square).



- for larger resistances we need minimum width poly (often combined with a *serpantine* shape) to save on area
- corner squares count as half<sup>2</sup> squares
- for predicatability and matching we may need wider tracks without corners

<sup>&</sup>lt;sup>2</sup>effective resistance  $\approx 0.56R_s$ 

# Components for IC Design Capacitors В B fringe capacitor parallel tracks over underlying conductor metal-insulator-metal capacitor poly-insulator-poly capacitor (e.g. bulk silicon) (specialist analog process with 2 poly layers)

- Capacitance to underlying conductor  $C = C_a w l + 2 C_f l$
- Coupling capacitance to adjacent track C = C<sub>c</sub> l/s where C<sub>a</sub>, C<sub>f</sub>, C<sub>c</sub> are constants for a given layer and process *in digital designs our only aim is to minimise parasitic capacitance*